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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

### Details

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Details	
Product Status	Obsolete
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I <sup>2</sup> S, POR, PWM, WDT
Number of I/O	76
Program Memory Size	320KB (320K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	34K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2361b40f80laakxuma1

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# XC2361B, XC2363B, XC2364B, XC2365B XC2000 Family / Value Line

### **Table of Contents**

4.7 4.7.1 4.7.2 4.7.2.1 4.7.2.2 4.7.2.3 4.7.3 4.7.3 4.7.4 4.7.5 4.7.5.1 4.7.6	AC Parameters       94         Testing Waveforms       94         Definition of Internal Timing       95         Phase Locked Loop (PLL)       96         Wakeup Clock       99         Selecting and Changing the Operating Frequency       99         External Clock Input Parameters       100         Pad Properties       102         External Bus Timing       106         Bus Cycle Control with the READY Input       111         Synchronous Serial Interface Timing       114
4.7.6 4.7.7	Synchronous Serial Interface Timing       114         Debug Interface Timing       118
<b>5</b> 5.1 5.2 5.3	Package and Reliability124Packaging124Thermal Considerations126Quality Declarations127



Tabl	e 6 Pin De	efinitior	is and	Functions (cont'd)
Pin	Symbol	Ctrl.	Туре	Function
36	P2.12	O0 / I	St/B	Bit 12 of Port 2, General Purpose Input/Output
	U0C0_SELO 4	01	St/B	USIC0 Channel 0 Select/Control 4 Output
	U0C1_SELO 3	O2	St/B	USIC0 Channel 1 Select/Control 3 Output
	TXDC2	03	St/B	CAN Node 2 Transmit Data Output
	READY	IH	St/B	External Bus Interface READY Input
37	P2.11	O0 / I	St/B	Bit 11 of Port 2, General Purpose Input/Output
	U0C0_SELO 2	01	St/B	USIC0 Channel 0 Select/Control 2 Output
	U0C1_SELO 2	02	St/B	USIC0 Channel 1 Select/Control 2 Output
	BHE/WRH	ОН	St/B	<b>External Bus Interf. High-Byte Control Output</b> Can operate either as Byte High Enable (BHE) or as Write strobe for High Byte (WRH).
39	P2.0	O0 / I	St/B	Bit 0 of Port 2, General Purpose Input/Output
	AD13	OH / IH	St/B	External Bus Interface Address/Data Line 13
	RxDC0C	I	St/B	CAN Node 0 Receive Data Input
	T5INB	I	St/B	GPT12E Timer T5 Count/Gate Input
40	P2.1	O0 / I	St/B	Bit 1 of Port 2, General Purpose Input/Output
	TxDC0	01	St/B	CAN Node 0 Transmit Data Output
	AD14	OH / IH	St/B	External Bus Interface Address/Data Line 14
	T5EUDB	I	St/B	GPT12E Timer T5 External Up/Down Control Input
	ESR1_5	I	St/B	ESR1 Trigger Input 5
41	P2.2	O0 / I	St/B	Bit 2 of Port 2, General Purpose Input/Output
	TxDC1	01	St/B	CAN Node 1 Transmit Data Output
	AD15	OH / IH	St/B	External Bus Interface Address/Data Line 15
	ESR2_5	I	St/B	ESR2 Trigger Input 5



Table	e 6 Pin De	finitior	ns and	Functions (cont'd)
Pin	Symbol	Ctrl.	Туре	Function
59	P10.0	O0 / I	St/B	Bit 0 of Port 10, General Purpose Input/Output
	U0C1_DOUT	01	St/B	USIC0 Channel 1 Shift Data Output
	CCU60_CC6 0	O2	St/B	CCU60 Channel 0 Output
	AD0	OH / IH	St/B	External Bus Interface Address/Data Line 0
	CCU60_CC6 0INA	I	St/B	CCU60 Channel 0 Input
	ESR1_2	I	St/B	ESR1 Trigger Input 2
	U0C0_DX0A	I	St/B	USIC0 Channel 0 Shift Data Input
	U0C1_DX0A	I	St/B	USIC0 Channel 1 Shift Data Input
60	P10.1	O0 / I	St/B	Bit 1 of Port 10, General Purpose Input/Output
	U0C0_DOUT	01	St/B	USIC0 Channel 0 Shift Data Output
	CCU60_CC6 1	O2	St/B	CCU60 Channel 1 Output
	AD1	OH / IH	St/B	External Bus Interface Address/Data Line 1
	CCU60_CC6 1INA	I	St/B	CCU60 Channel 1 Input
	U0C0_DX1A	I	St/B	USIC0 Channel 0 Shift Clock Input
	U0C0_DX0B	I	St/B	USIC0 Channel 0 Shift Data Input
61	P0.3	O0 / I	St/B	Bit 3 of Port 0, General Purpose Input/Output
	U1C0_SELO 0	O1	St/B	USIC1 Channel 0 Select/Control 0 Output
	U1C1_SELO 1	O2	St/B	USIC1 Channel 1 Select/Control 1 Output
	CCU61_COU T60	O3	St/B	CCU61 Channel 0 Output
	A3	OH	St/B	External Bus Interface Address Line 3
	U1C0_DX2A	I	St/B	USIC1 Channel 0 Shift Control Input
	RxDC0B	I	St/B	CAN Node 0 Receive Data Input



Tabl	e 6 Pin De	finitior	ns and	Functions (cont'd)
Pin	Symbol	Ctrl.	Туре	Function
62	P10.2	O0 / I	St/B	Bit 2 of Port 10, General Purpose Input/Output
	U0C0_SCLK OUT	01	St/B	USIC0 Channel 0 Shift Clock Output
	CCU60_CC6 2	O2	St/B	CCU60 Channel 2 Output
	AD2	OH / IH	St/B	External Bus Interface Address/Data Line 2
	CCU60_CC6 2INA	I	St/B	CCU60 Channel 2 Input
_	U0C0_DX1B	I	St/B	USIC0 Channel 0 Shift Clock Input
63	P0.4	O0 / I	St/B	Bit 4 of Port 0, General Purpose Input/Output
	U1C1_SELO 0	01	St/B	USIC1 Channel 1 Select/Control 0 Output
	U1C0_SELO 1	O2	St/B	USIC1 Channel 0 Select/Control 1 Output
	CCU61_COU T61	O3	St/B	CCU61 Channel 1 Output
	A4	OH	St/B	External Bus Interface Address Line 4
	U1C1_DX2A	I	St/B	USIC1 Channel 1 Shift Control Input
	RxDC1B	I	St/B	CAN Node 1 Receive Data Input
	ESR2_8	I	St/B	ESR2 Trigger Input 8
65	P2.13	O0 / I	St/B	Bit 13 of Port 2, General Purpose Input/Output
	U2C1_SELO 2	01	St/B	USIC2 Channel 1 Select/Control 2 Output
	RxDC2D	I	St/B	CAN Node 2 Receive Data Input
66	P2.10	O0 / I	St/B	Bit 10 of Port 2, General Purpose Input/Output
	U0C1_DOUT	01	St/B	USIC0 Channel 1 Shift Data Output
	U0C0_SELO 3	O2	St/B	USIC0 Channel 0 Select/Control 3 Output
	CC2_CC23	O3 / I	St/B	CAPCOM2 CC23IO Capture Inp./ Compare Out.
	A23	ОН	St/B	External Bus Interface Address Line 23
	U0C1_DX0E	I	St/B	USIC0 Channel 1 Shift Data Input
	CAPINA	I	St/B	GPT12E Register CAPREL Capture Input



Table	1	1		Functions (cont'd)		
Pin	Symbol	Ctrl.	Туре			
81	P1.1	O0 / I	St/B	Bit 1 of Port 1, General Purpose Input/Output		
	U1C0_SELO 5	O2	St/B	USIC1 Channel 0 Select/Control 5 Output		
	U2C1_DOUT	O3	St/B	USIC2 Channel 1 Shift Data Output		
	A9	OH	St/B	External Bus Interface Address Line 9		
	ESR2_3	I	St/B	ESR2 Trigger Input 3		
	U2C1_DX0C	I	St/B	USIC2 Channel 1 Shift Data Input		
82	P10.10	O0 / I	St/B	Bit 10 of Port 10, General Purpose Input/Output		
	U0C0_SELO 0	01	St/B	USIC0 Channel 0 Select/Control 0 Output		
	CCU60_COU T63	O2	St/B	CCU60 Channel 3 Output		
	AD10	OH / IH	St/B	External Bus Interface Address/Data Line 10		
	U0C0_DX2C	I	St/B	USIC0 Channel 0 Shift Control Input		
	U0C1_DX1A	I	St/B	USIC0 Channel 1 Shift Clock Input		
	TDI_B	IH	St/B	JTAG Test Data Input If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it.		
83	P10.11	O0 / I	St/B	Bit 11 of Port 10, General Purpose Input/Output		
	U1C0_SCLK OUT	01	St/B	USIC1 Channel 0 Shift Clock Output		
	BRKOUT	02	St/B	OCDS Break Signal Output		
	AD11	OH / IH	St/B	External Bus Interface Address/Data Line 11		
	U1C0_DX1D	I	St/B	USIC1 Channel 0 Shift Clock Input		
	RxDC2B	I	St/B	CAN Node 2 Receive Data Input		
	TMS_B	IH	St/B	<b>JTAG Test Mode Selection Input</b> If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it.		



### **Functional Description**

Address Area	Start Loc.	End Loc.	Area Size <sup>2)</sup>	Notes
Reserved for DSRAM	00'8000 <sub>H</sub>	00'9FFF <sub>H</sub>	8 Kbytes	
External memory area	00'000 <sub>H</sub>	00'7FFF <sub>H</sub>	32 Kbytes	

### Table 8 XC236xB Memory Map (cont'd)<sup>1)</sup>

 Accesses to the shaded areas are reserved. In devices with external bus interface these accesses generate external bus accesses.

- 2) The areas marked with "<" are slightly smaller than indicated, see column "Notes".
- 3) The uppermost 4-Kbyte sector of the first Flash segment is reserved for internal use (C0'F000<sub>H</sub> to C0'FFFF<sub>H</sub>).
- 4) Several pipeline optimizations are not active within the external IO area. This is necessary to control external peripherals properly.

This common memory space consists of 16 Mbytes organized as 256 segments of 64 Kbytes; each segment contains four data pages of 16 Kbytes. The entire memory space can be accessed bytewise or wordwise. Portions of the on-chip DPRAM and the register spaces (ESFR/SFR) additionally are directly bit addressable.

The internal data memory areas and the Special Function Register areas (SFR and ESFR) are mapped into segment 0, the system segment.

The Program Management Unit (PMU) handles all code fetches and, therefore, controls access to the program memories such as Flash memory and PSRAM.

The Data Management Unit (DMU) handles all data transfers and, therefore, controls access to the DSRAM and the on-chip peripherals.

Both units (PMU and DMU) are connected to the high-speed system bus so that they can exchange data. This is required if operands are read from program memory, code or data is written to the PSRAM, code is fetched from external memory, or data is read from or written to external resources. These include peripherals on the LXBus such as USIC or MultiCAN. The system bus allows concurrent two-way communication for maximum transfer performance.

**Up to 16 Kbytes of on-chip Program SRAM (PSRAM)** are provided to store user code or data. The PSRAM is accessed via the PMU and is optimized for code fetches. A section of the PSRAM with programmable size can be write-protected.

Note: The actual size of the PSRAM depends on the quoted device type.



### **Functional Description**

# 3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LXBus (MultiCAN and the USIC modules). The LXBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections<sup>1)</sup>:

- Address Bus Width with a range of 0 ... 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes ... 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

External  $\overline{CS}$  signals (address windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.

Access to very slow memories or modules with varying access times is supported by a special 'Ready' function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

<sup>1)</sup> Bus modes are switched dynamically if several address windows with different mode settings are used.



### **Functional Description**

# 3.4 Memory Protection Unit (MPU)

The XC236xB's Memory Protection Unit (MPU) protects user-specified memory areas from unauthorized read, write, or instruction fetch accesses. The MPU can protect the whole address space including the peripheral area. This completes established mechanisms such as the register security mechanism or stack overrun/underrun detection.

Four Protection Levels support flexible system programming where operating system, low level drivers, and applications run on separate levels. Each protection level permits different access restrictions for instructions and/or data.

Every access is checked (if the MPU is enabled) and an access violating the permission rules will be marked as invalid and leads to a protection trap.

A set of protection registers for each protection level specifies the address ranges and the access permissions. Applications requiring more than 4 protection levels can dynamically re-program the protection registers.

# 3.5 Memory Checker Module (MCHK)

The XC236xB's Memory Checker Module calculates a checksum (fractional polynomial division) on a block of data, often called Cyclic Redundancy Code (CRC). It is based on a 32-bit linear feedback shift register and may, therefore, also be used to generate pseudo-random numbers.

The Memory Checker Module is a 16-bit parallel input signature compression circuitry which enables error detection within a block of data stored in memory, registers, or communicated e.g. via serial communication lines. It reduces the probability of error masking due to repeated error patterns by calculating the signature of blocks of data.

The polynomial used for operation is configurable, so most of the commonly used polynomials may be used. Also, the block size for generating a CRC result is configurable via a local counter. An interrupt may be generated if testing the current data block reveals an error.

An autonomous CRC compare circuitry is included to enable redundant error detection, e.g. to enable higher safety integrity levels.

The Memory Checker Module provides enhanced fault detection (beyond parity or ECC) for data and instructions in volatile and non volatile memories. This is especially important for the safety and reliability of embedded systems.



# XC2361B, XC2363B, XC2364B, XC2365B XC2000 Family / Value Line

### **Functional Description**

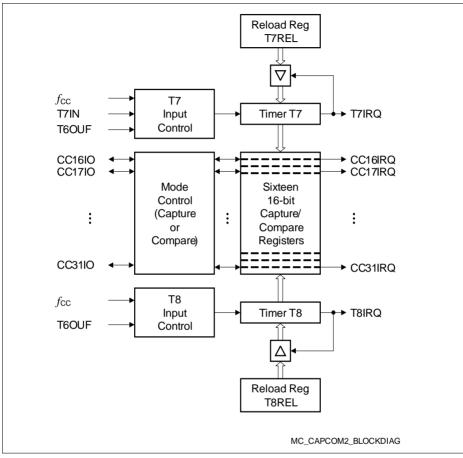


Figure 6 CAPCOM Unit Block Diagram



# 4.3.3 Power Consumption

The power consumed by the XC236xB depends on several factors such as supply voltage, operating frequency, active circuits, and operating temperature. The power consumption specified here consists of two components:

- The switching current  $I_{\rm S}$  depends on the device activity
- The leakage current I<sub>LK</sub> depends on the device temperature

To determine the actual power consumption, always both components, switching current  $I_{\rm S}$  and leakage current  $I_{\rm LK}$  must be added:

 $I_{\text{DDP}} = I_{\text{S}} + I_{\text{LK}}.$ 

Note: The power consumption values are not subject to production test. They are verified by design/characterization.

To determine the total power consumption for dimensioning the external power supply, also the pad driver currents must be considered.

The given power consumption parameters and their values refer to specific operating conditions:

Active mode:

Regular operation, i.e. peripherals are active, code execution out of Flash.

Stopover mode:

Crystal oscillator and PLL stopped, Flash switched off, clock in domain DMP\_1 stopped.

Note: The maximum values cover the complete specified operating range of all manufactured devices.

The typical values refer to average devices under typical conditions, such as nominal supply voltage, room temperature, application-oriented activity.

After a power reset, the decoupling capacitors for  $V_{\rm DDIM}$  and  $V_{\rm DDI1}$  are charged with the maximum possible current.

For additional information, please refer to Section 5.2, Thermal Considerations.

Note: Operating Conditions apply.



- 2) Flash module 1 can be erased/programmed while code is executed and/or data is read from Flash module 0.
- 3) Value of IMB\_IMBCTRL.WSFLASH.
- 4) Programming and erase times depend on the internal Flash clock source. The control state machine needs a few system clock cycles. This increases the stated durations noticably only at extremely low system clock frequencies.

Access to the XC236xB Flash modules is controlled by the IMB. Built-in prefetch mechanisms optimize the performance for sequential access.

Flash access waitstates only affect non-sequential access. Due to prefetch mechanisms, the performance for sequential access (depending on the software structure) is only partially influenced by waitstates.



# 4.7 AC Parameters

These parameters describe the dynamic behavior of the XC236xB.

# 4.7.1 Testing Waveforms

These values are used for characterization and production testing (except pin XTAL1).

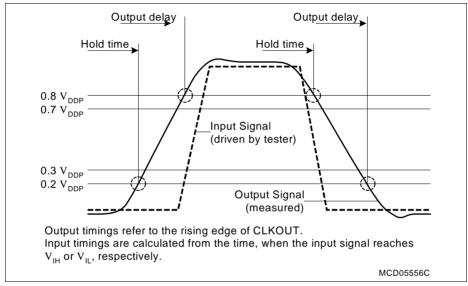
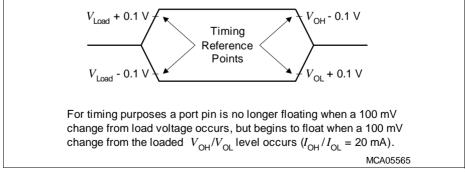
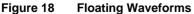


Figure 17 Input Output Waveforms







# 4.7.2 Definition of Internal Timing

The internal operation of the XC236xB is controlled by the internal system clock  $f_{SYS}$ .

Because the system clock signal  $f_{\rm SYS}$  can be generated from a number of internal and external sources using different mechanisms, the duration of the system clock periods (TCSs) and their variation (as well as the derived external timing) depend on the mechanism used to generate  $f_{\rm SYS}$ . This must be considered when calculating the timing for the XC236xB.

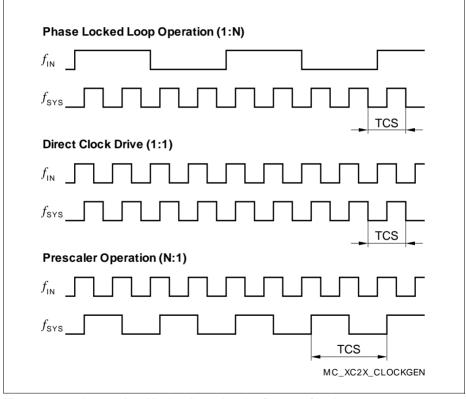


Figure 19 Generation Mechanisms for the System Clock

Note: The example of PLL operation shown in **Figure 19** uses a PLL factor of 1:4; the example of prescaler operation uses a divider factor of 2:1.

The specification of the external timing (AC Characteristics) depends on the period of the system clock (TCS).



# **Direct Drive**

When direct drive operation is selected (SYSCON0.CLKSEL =  $11_B$ ), the system clock is derived directly from the input clock signal CLKIN1:

 $f_{SYS} = f_{IN}$ .

The frequency of  $f_{SYS}$  is the same as the frequency of  $f_{IN}$ . In this case the high and low times of  $f_{SYS}$  are determined by the duty cycle of the input clock  $f_{IN}$ .

Selecting Bypass Operation from the XTAL1<sup>1)</sup> input and using a divider factor of 1 results in a similar configuration.

### Prescaler Operation

When prescaler operation is selected (SYSCON0.CLKSEL =  $10_B$ , PLLCON0.VCOBY =  $1_B$ ), the system clock is derived either from the crystal oscillator (input clock signal XTAL1) or from the internal clock source through the output prescaler K1 (= K1DIV+1):

 $f_{\text{SYS}} = f_{\text{OSC}} / \text{K1}.$ 

If a divider factor of 1 is selected, the frequency of  $f_{\rm SYS}$  equals the frequency of  $f_{\rm OSC}$ . In this case the high and low times of  $f_{\rm SYS}$  are determined by the duty cycle of the input clock  $f_{\rm OSC}$  (external or internal).

The lowest system clock frequency results from selecting the maximum value for the divider factor K1:

 $f_{\rm SYS} = f_{\rm OSC} / 1024.$ 

# 4.7.2.1 Phase Locked Loop (PLL)

When PLL operation is selected (SYSCON0.CLKSEL =  $10_B$ , PLLCON0.VCOBY =  $0_B$ ), the on-chip phase locked loop is enabled and provides the system clock. The PLL multiplies the input frequency by the factor **F** ( $f_{SYS} = f_{IN} \times F$ ).

**F** is calculated from the input divider P (= PDIV+1), the multiplication factor N (= NDIV+1), and the output divider K2 (= K2DIV+1):

 $(F = N / (P \times K2)).$ 

The input clock can be derived either from an external source at XTAL1 or from the onchip clock source.

The PLL circuit synchronizes the system clock to the input clock. This synchronization is performed smoothly so that the system clock frequency does not change abruptly.

Adjustment to the input clock continuously changes the frequency of  $f_{\text{SYS}}$  so that it is locked to  $f_{\text{IN}}$ . The slight variation causes a jitter of  $f_{\text{SYS}}$  which in turn affects the duration of individual TCSs.

<sup>1)</sup> Voltages on XTAL1 must comply to the core supply voltage  $V_{\text{DDIM}}$ .



Parameter	Symbol		Values		Unit	Note /											
		Min.	Тур.	Max.		Test Condition											
Rise and Fall times (10% - 90%)	t <sub>RF</sub> CC	-	-	23 + 0.6 x C <sub>L</sub>	ns	$C_{L} \ge 20 \text{ pF};$ $C_{L} \le 100 \text{ pF};$ Driver_Strength = Medium											
		_	-	11.6 + 0.22 x C <sub>L</sub>	ns	$C_{L} \ge 20 \text{ pF};$ $C_{L} \le 100 \text{ pF};$ Driver_Strength = Strong; Driver_Edge= Medium											
													-	-	4.2 + 0.14 x C <sub>L</sub>	ns	$C_{L} \ge 20 \text{ pF};$ $C_{L} \le 100 \text{ pF};$ Driver_Strength = Strong; Driver_Edge= Sharp
		-	-	20.6 + 0.22 x C <sub>L</sub>	ns	$C_{L} \ge 20 \text{ pF};$ $C_{L} \le 100 \text{ pF};$ Driver_Strength = Strong; Driver_Edge= Slow											
		-	-	212 + 1.9 x C <sub>L</sub>	ns	$C_{L} \ge 20 \text{ pF};$ $C_{L} \le 100 \text{ pF};$ Driver_Strength = Weak											

Table 28 Standard Pad Parameters for Upper Voltage Range (cont'd)

1) An output current above  $|I_{OXnom}|$  may be drawn from up to three pins at the same time. For any group of 16 neighboring output pins, the total output current in each direction ( $\Sigma I_{OL}$  and  $\Sigma - I_{OH}$ ) must remain below 50 mA.



### Variable Memory Cycles

External bus cycles of the XC236xB are executed in five consecutive cycle phases (AB, C, D, E, F). The duration of each cycle phase is programmable (via the TCONCSx registers) to adapt the external bus cycles to the respective external module (memory, peripheral, etc.).

The duration of the access phase can optionally be controlled by the external module using the READY handshake input.

This table provides a summary of the phases and the ranges for their length.

Table 31 Programmable Bus Cycle Phases (see timing diagram	Table 31	Programmable Bus Cycle Phases (see timing diagrams)
--	----------	---

Bus Cycle Phase	Parameter	Valid Values	Unit
Address setup phase, the standard duration of this phase (1 $\dots$ 2 TCS) can be extended by 0 $\dots$ 3 TCS if the address window is changed	tpAB	1 2 (5)	TCS
Command delay phase	tpC	03	TCS
Write Data setup/MUX Tristate phase	tpD	0 1	TCS
Access phase	tpE	1 32	TCS
Address/Write Data hold phase	tpF	03	TCS

Note: The bandwidth of a parameter (from minimum to maximum value) covers the whole operating range (temperature, voltage) as well as process variations. Within a given device, however, this bandwidth is smaller than the specified range. This is also due to interdependencies between certain parameters. Some of these interdependencies are described in additional notes (see standard timing).

Note: Operating Conditions apply.

**Table 32** is valid under the following conditions:  $C_L = 20 \text{ pF}$ ; voltage\_range= upper ; voltage\_range= upper

Table 32	External Bus	Timing for	Upper Voltage Range
----------	--------------	------------	---------------------

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
$\frac{\text{Output valid delay for }\overline{\text{RD}},}{\text{WR}(L/H)}$	<i>t</i> <sub>10</sub> CC	-	7	13	ns	
Output valid delay for BHE, ALE	<i>t</i> <sub>11</sub> CC	-	7	14	ns	
Address output valid delay for A23 A0	<i>t</i> <sub>12</sub> CC	-	8	14	ns	



# XC2361B, XC2363B, XC2364B, XC2365B XC2000 Family / Value Line

**Electrical Parameters** 

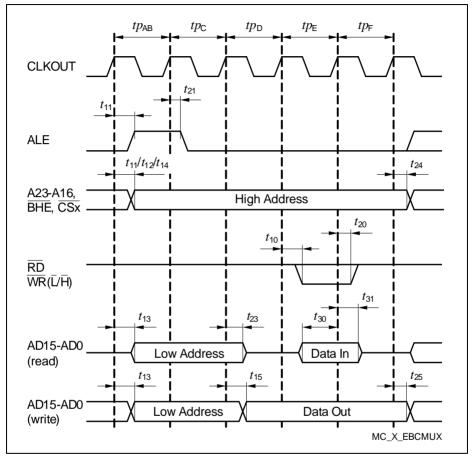


Figure 23 Multiplexed Bus Cycle



#### Table 36 USIC SSC Slave Mode Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
Data input DX0 hold time from clock input DX1 receive edge <sup>1)</sup>	<i>t</i> <sub>13</sub> SR	5	-	-	ns	
Data output DOUT valid time	<i>t</i> <sub>14</sub> CC	7	-	33	ns	

 These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

**Table 37** is valid under the following conditions:  $C_L = 20 \text{ pF}$ ; *SSC*= slave ; voltage\_range= lower

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.	1	Test Condition
Select input DX2 setup to first clock input DX1 transmit edge <sup>1)</sup>	<i>t</i> <sub>10</sub> SR	7	-	-	ns	
Select input DX2 hold after last clock input DX1 receive edge <sup>1)</sup>	<i>t</i> <sub>11</sub> SR	7	-	-	ns	
Receive data input setup time to shift clock receive edge <sup>1)</sup>	<i>t</i> <sub>12</sub> SR	7	-	-	ns	
Data input DX0 hold time from clock input DX1 receive edge <sup>1)</sup>	<i>t</i> <sub>13</sub> SR	5	-	-	ns	
Data output DOUT valid time	<i>t</i> <sub>14</sub> CC	8	-	41	ns	

#### Table 37 USIC SSC Slave Mode Timing for Lower Voltage Range

 These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).



### Table 40 JTAG Interface Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note /	
		Min.	Тур.	Max.		Test Condition	
TCK low time	t <sub>3</sub> SR	16	-	-	ns		
TCK clock rise time	t <sub>4</sub> SR	-	-	8	ns		
TCK clock fall time	t <sub>5</sub> SR	-	-	8	ns		
TDI/TMS setup to TCK rising edge	t <sub>6</sub> SR	6	-	-	ns		
TDI/TMS hold after TCK rising edge	t <sub>7</sub> SR	6	-	-	ns		
TDO valid from TCK falling edge (propagation delay) <sup>2)</sup>	t <sub>8</sub> CC	-	25	29	ns		
TDO high impedance to valid output from TCK falling edge <sup>3)2)</sup>	t <sub>9</sub> CC	-	25	29	ns		
TDO valid output to high impedance from TCK falling edge <sup>2)</sup>	<i>t</i> <sub>10</sub> CC	-	25	29	ns		
TDO hold after TCK falling edge <sup>2)</sup>	<i>t</i> <sub>18</sub> CC	5	-	-	ns		

1) Under typical conditions, the JTAG interface can operate at transfer rates up to 20 MHz.

2) The falling edge on TCK is used to generate the TDO timing.

3) The setup time for TDO is given implicitly by the TCK cycle time.

**Table 41** is valid under the following conditions:  $C_1 = 20 \text{ pF}$ ; voltage\_range= lower

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
TCK clock period	t <sub>1</sub> SR	50	-	_	ns	
TCK high time	t <sub>2</sub> SR	16	-	_	ns	
TCK low time	t <sub>3</sub> SR	16	-	_	ns	
TCK clock rise time	t <sub>4</sub> SR	_	-	8	ns	
TCK clock fall time	t <sub>5</sub> SR	-	-	8	ns	
TDI/TMS setup to TCK rising edge	t <sub>6</sub> SR	6	-	-	ns	

 Table 41
 JTAG Interface Timing for Lower Voltage Range



#### Package and Reliability

# 5 Package and Reliability

The XC2000 Family devices use the package type PG-LQFP (Plastic Green - Low Profile Quad Flat Package). The following specifications must be regarded to ensure proper integration of the XC236xB in its target environment.

# 5.1 Packaging

These parameters specify the packaging rather than the silicon.

Parameter	Symbol	Lim	it Values	Unit	Notes
		Min.	Max.		
Exposed Pad Dimension	$E x \times E y$	-	5.2 × 5.2	mm	-
Power Dissipation	$P_{DISS}$	-	0.8	W	-
Thermal resistance	$R_{\Theta JA}$	_	54	K/W	No thermal via <sup>1)</sup>
Junction-Ambient			49	K/W	4-layer, no pad <sup>2)</sup>
			27	K/W	4-layer, pad <sup>3)</sup>

#### Table 42 Package Parameters (PG-LQFP-100-8/-15)

1) Device mounted on a 4-layer board without thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad soldered to the board.

Note: To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground, independent of the thermal requirements. Board layout examples are given in an application note.

### Package Compatibility Considerations

The XC236xB is a member of the XC2000 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the Exposed Pad (if present) may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.